

Automatic RF Techniques Group

66th Microwave Measurements Conference

Measurements of High Performance Devices and Applications

Marriott Hotel, Washington DC, USA

December 1-2nd 2005

FIRST CALL FOR PAPERS

Join us in exploring cutting-edge microwave measurements for both the industrial and government-related engineering communities. We encourage submission of original papers demonstrating your characterization approach to emerging microwave devices and circuits: Papers are invited on the topics of:

- Test Challenges for High Power Devices (> 10 Watts)
 - testing of high voltage and high power devices such as SiC, GaN, LDMOS and SiGe
 - nondestructive testing of defective high power devices
 - on-wafer characterization and tests
- Measurements on Emerging Technologies:
 - surveillance, deep space, and secure and commercial communications
 - reliability characterization of RF-MEMS devices and circuits
 - mixed-signal and multifunction modules and components
 - carbon nanotube (CNT) devices
- Measurement Accuracy
- Nonlinear Measurement:
 - CW and modulated signal circuit characterization
 - large-signal measurements
 - the foundry as a key participant

as well as other areas of automated RF measurements.

DEADLINES

September 9th Electronic Abstract/Summary due

October 14th Electronic full camera-ready paper in pdf format due

Paper acceptance and classification will be communicated by Sept. 20th, 2005 Information can be found in the Abstract/Summary Submission Instructions on our Web site, www.arftg.org

NIST/ARFTG MEASUREMENTS SHORT COURSE

Join us in a practical microwave measurement tutorial. Day 1: Microwave measurements overview; circuit theory; VNA; interconnects and IC test fixtures and probing, RF connectors; on-wafer measurements; power; thermal noise; phase noise; Day 2: Uncertainty analysis; digital modulation; time-domain network analysis; overview of wireless test instrumentation and measurement; introduction to nonlinear measurements. Fee: \$400 for 1-1/2 day course. Contact Dave Walker (dwalker@boulder.nist.gov) 303-497-5490 for more information.

NONLINEAR MEASUREMENTS WORKSHOP

We will discuss measurement techniques to accurately characterize the system-induced nonlinear behavior of broad-bandwidth modulated signals. We will focus on methods that provide sufficient spectral detail for digitally modulated signals transmitted using formats such as OFDM and spread spectrum. We will discuss existing methods and possible new solutions to the broadband measurement problem. Contact Kate Remley (remley@boulder.nist.gov) about participation.

EXHIBITS

The 66th ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information (j.l.tauritz@ieee.org).

Conference Chair

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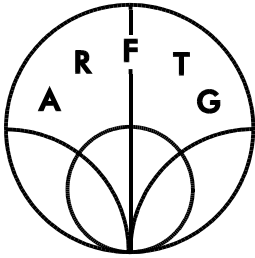
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w.arftg.org



WWW



ELECTRONIC SUBMISSION DEADLINES

Electronic Abstract and Summary

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Publication-ready paper in PDF format

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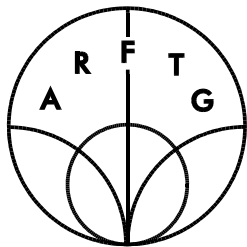


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